

**Notice of References Cited**

Application/Control No.

10/681,556

Applicant(s)/Patent Under  
Reexamination  
CHANG ET AL.

Examiner

Ben C. Wang

Art Unit

2192

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mitchell et al., "Toward a definition of run-time object-oriented metrics", July 22 <sup>nd</sup> , 2003, ECOOP, pp. 1-6
	V	Mitchell et al., "Run-tim Cohesion Metrics for the Analysis of Java Programs - preliminary results form the SPEC and Grande suites" (NUIM-CS-TR-2003-7), April 2003, National University of Ireland, Maynooth, pp. 1-15
	W	Mitchell et al., "Run-tim Cohesion Metrics for the Analysis of Java Programs - preliminary results from the SPEC and Grande suites" (NUIM-CS-TR-2003-08), April 2003, National University of Ireland, Maynooth, pp. 1-11
	X	Michael et al., "Metrics for Measuring the Effectiveness of Software-Testing Tools", 2002, IEEE, pp. 1-12

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.